



MeX[®]

With MeX 6.1 Alicona provides a milestone in traceable metrology with the SEM

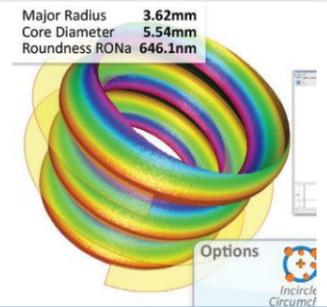
alicona

Turn your SEM into a 3D measurement device

MeX is a stand alone software package that turns any SEM with digital imaging into a true surface metrology device. Using stereoscopic images the software automatically retrieves 3D information and presents a highly accurate, robust and dense 3D data set which is then used to perform traceable metrology examination. MeX is extremely easy to use. The software is self installing and works completely independently of any third drivers or components.

MeX automatically merges single measurements from various directions into a complete 3D data set

If required, a component can be measured in 3D from different perspectives. Measurements from various positions are automatically merged into a complete 3D data set. The "Real3D" technology allows the component's visualization from different angles plus a measurement of contour, difference to e.g. measure wear, and form. This way, surface parameters such as undercuts that are normally difficult to access are measured quickly and effortlessly.



MeX 6.1 measures angles, distances, circles, thread pitch etc.

With MeX 6.1 towards traceable 3D metrology with the SEM

MeX 6.1 supports Windows 8 and comes in both 32bit and 64bit versions.

MeX 6.1 is the recent software upgrade with new features for extended measurements. Latest technologies for applications in micro coordinate measurement make any SEM to a comprehensive metrology tool that open up new fields of use:

Contour Measurement

Users measure angles, distances, circles, incircles, circumcircles, thread pitch etc. from every position. In addition, the contour measurement module includes roundness measurement.

Difference Measurement

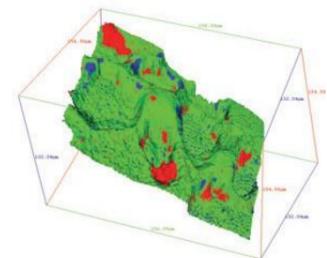
Difference measurement is used to numerically compare two different geometries.

Form Measurement

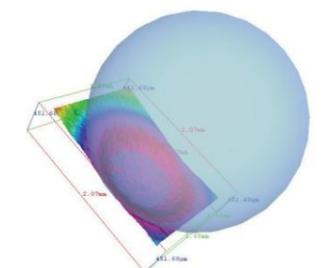
Automatic fitting of spheres, cones and cylinders allow the visualization and form measurement of tools and other components.

Contour, difference and form measurement complement already existing measurement modules:

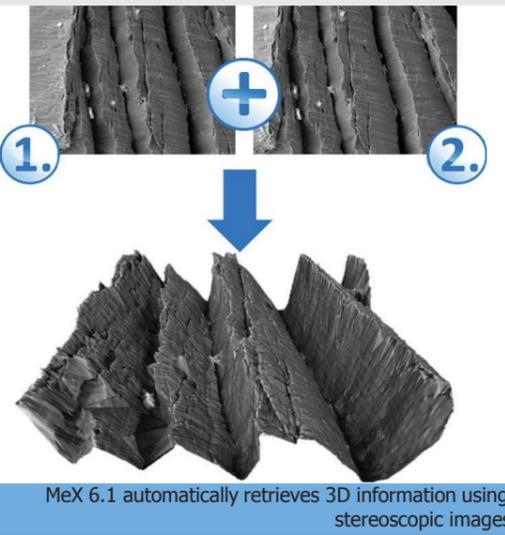
- » **Profile-Form Measurement**
Height steps, radii, angle measurement etc.
- » **Profile-Roughness Measurement**
Ra, Rq, Rz accordant to ISO 4287, 4288
- » **Surface Texture Measurement**
Areal roughness measurement accordant to ISO 25178
- » **Volume Measurement**
Verification of voids and protrusions
- » **2D Image Analysis:**
Manual or semi automatic measurement of simple primitives



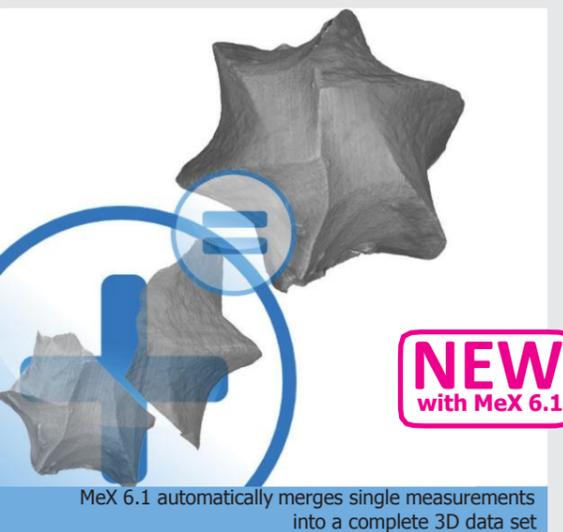
MeX 6.1 compares two different geometries



MeX 6.1 also includes form fitting functions



MeX 6.1 automatically retrieves 3D information using stereoscopic images



MeX 6.1 automatically merges single measurements into a complete 3D data set

NEW
with MeX 6.1

- MeX[®] 6.1 » **Undercuts and larger field of views** now measurable
- MeX[®] 6.1 » **New features such as form fitting functionalities** available
- MeX[®] 6.1 » **Re-designed measurement modules provide higher usability**

Questions about upgrading?

Need to update your contact information to get our latest news and product releases?

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